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	AN	4-	1	3	5	1	7	6	12/1992	Japan (Utility Model)	-	-	x-Abst.			
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MCE	AS	3 6 8 0 0 3 5						5	07/1972	Teagno et al.	-439	-329	-	
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	AU	4	0	8	7	1	5	1	05/1978	Robert et al.	439	188		
	AV	5	0	5	1	1	0	0	09/1991	Kato et al.	439	140	-	
	AW	5	0	9	0	9	2	5	02/1992	Sato et al.	-439	-862	-	
	AX	5	2	3	2	3	7	3	08/1993	Sawada	-439	-140	-	
	AY	5	3	0	8	2	6	5	05/1994	Kaneko	-439	-752	-	
	AZ	5	6	0	5	1	5	0	02/1997	Radons et al.	-128	- 630	_	
	AA2	5	6	4	7	7	7	8	07/1997	Yamaguchi et a	-439	-752	-	
	AB2	6	2	8	0	2	6	2	08/2001	Tanaka	-439	-752	-	
	AC2	6	3	0	9	2	6	2	10/2001	Morris	-439	-862	-	
	AD2	6	3	1	5	6	2	1	11/2001	Natori et al.	-439	-862	-	
	AE2	6	3	4	3	9	6	0	02/2002	Sato		-439	-701	-
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